



EMC COMPO 2002

**3rd International Workshop on
Electromagnetic Compatibility of Integrated Circuits**
*3^{ème} Conférence Internationale sur la Compatibilité
Electromagnétique des Circuits Intégrés*

Workshop Record

**Hôtel ATRIA Toulouse - France
Toulouse - FRANCE
November 14 – 15 th, 2002**

<http://www.emccompo.org>



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WELCOME TO THE EMC Compo 02 Workshop

On behalf of the French Society of Electronics and Electricity and the IEEE French section, the local committee is proud to host this 3rd event on electromagnetic compatibility dedicated to integrated circuits.

This year's workshop will consist of 28 oral and poster presentations, and 4 exhibitions. We invited two outstanding contributors : Bob Ross, Mentor Graphics, USA, who directed the IBIS committee for many years and supported the introduction of EMC information within the IBIS standard, and Ross Carlton, Motorola Austin, USA, member of the international standardization group dedicated to EMC for integrated circuits at IEC.

We invite you to learn more about measurement methods, models, tools and design techniques for improved electromagnetic compatibility, during those 2 technical days.

Don't miss the exhibition area and the evening dinner aboard the "Occitania".

The program committee, the French section of the IEEE society, the regional section of SEE and the local committee wish you a very fruitful workshop in Toulouse.

BIENVENUE AU WORKSHOP EMC Compo 02

Sous l'égide de la société française des électriciens et électroniciens, et de la section française de la société IEEE, le comité d'organisation est heureux de vous accueillir pour ce 3^{ème} workshop dédié à la compatibilité électromagnétique des circuits intégrés.

Le workshop cette année est constitué de 28 présentations orales et posters, ainsi que 4 exhibitions dans le hall. Nous avons invité deux personnalités ayant apporté une contribution exceptionnelle : Bob Ross, Mentor Graphics, qui a dirigé le groupe de standardisation IBIS, et aidé à l'introduction de données liées à la CEM des composants, ainsi que Ross Carlton, Motorola Austin, USA, membre du groupe de standardisation international à l'IEC, couvrant la CEM des circuits intégrés. Nous vous invitons, au travers des exposés techniques durant ces 2 jours, à approfondir vos connaissances en matière de méthodes de mesure, modélisation, outils et techniques de conception pour une meilleure compatibilité électromagnétique des composants.

Ne manquez pas les exhibitions ainsi que le dîner organisé à bord de l'Occitania.

Le comité de programme, la section française de la société IEEE, la section Midi-Pyrénées de SEE et le comité d'organisation vous souhaite un séjour agréable et profitable à Toulouse.



Professeur Etienne SICARD
EMC Compo 02 Chairman

TOPICS

The purpose of the workshop *EMC Compo 2002* is to address the emission and susceptibility issues for integrated circuits, either logic, analog or mixed logic/analog. The most recent advances in measurement methods, models, standards, tools and design methodologies will be discussed during the workshop.

The workshop is specifically focused on EMC for integrated circuits, with the following sub-topics:

- Measurement methods for emission of integrated circuits
- Measurement methods for susceptibility of integrated circuits
- Models & standards for predicting the emission of integrated circuits
- Education and e-learning related to EMC for ICs
- Use of IC models in Printed circuit board simulation
- Models for predicting the susceptibility of integrated circuits
- Design methodologies for improved EMC behavior of ICs
- Tools to handle EMC at IC level
- Prospective aspects of EMC in future generation ICs

OBJECTIFS

L'objectif de ce 3^{ème} Workshop, organisé par l'IERSET, l'INSA et la SEE est de réunir pendant deux jours à Toulouse la communauté d'ingénieurs et de chercheurs en compatibilité électromagnétique (CEM) des circuits intégrés.

Cet événement devrait attirer non seulement les industriels, centres de recherches et PME français, mais aussi les experts d'Italie, Allemagne, Espagne, Angleterre et USA.

Les domaines traités par EMC Compo 2002 seront :

- *les techniques de mesure d'émission et de susceptibilité des circuits intégrés*
- *la modélisation de l'émission des circuits intégrés*
- *les méthodes de conception pour un meilleur comportement CEM*
- *l'évolution des normes internationales en CEM des composants*
- *la formation et l'éducation à distance en CEM composants*
- *les outils de conception intégrant la CEM des composants*

Une exposition de matériel et logiciels relatifs à la CEM des composants se tiendra en parallèle à la conférence.

La langue officielle du workshop est l'anglais. Un résumé des présentations en français sera disponible pour l'ensemble des participants.

SCIENTIFIC PROGRAM/PROGRAMME SCIENTIFIQUE

Nov 14th 2002	
9:00 Opening by E. SICARD (Lesia, France)	Page
9:15 IBIS and ICEM B. ROSS (Mentor Graphics, USA)	10
9:45 Overview of standards in electromagnetic compatibility for integrated circuits R. CARLTON (Motorola, USA)	14
10:15 Coffee break	
Session: Measurement of Emission	Page
10:45 Measurement system for adjacent electrical field and magnetic field distributions on an IC package S. KAZAMA (Taiyo Yudenco Ltd, Japan)	15
11:15 GTEM cell facility use during project development phases for automotive O. MAURICE (Valeo, France), F. DE DARAN, F. LAFON (Valeo, France), R. OUSSEDRAT, I. BEN-YACOUB	19
11:45 Vectorial voltage measurement for Ics on multi-IC PWB M. COENEN (Philips Semiconductors, Holland), R. DERIKX	23
12:15 Lunch	
Session: Measurement of Susceptibility	Page
14:00 Modeling of bundle with radiated losses for BCI testing F. DUVAL (Esigelec France), B. MAZARI, O. MAURICE, F. FOUQUET, A. LOUIS, T. LE GUYADER	27
14:30 Selection of test signals and parametric estimation of susceptibility of integrated circuits to electromagnetic conducted disturbances J. KOLODZIEJSKY (Institute of Electron Technology, Poland)	31
15:00 Investigation on EMI effects in bandgap voltage references F. FIORI (Politecnico di Torino, Italy), P.S. CROVETTI	35

Poster Session	Page
15:30 Presentation :	
Radiated power measurements of electronic equipment in three dimensional TEM cells V. DENIAU (Inrets, France), J. RIOULT, M. HEDDEBAUT, B. DEMOULIN	39
A current shaping methodology for low EMI asynchronous circuits D. PANYASAK (TIMA, France), G. SICARD, M. RENAUDIN	43
Line geometry implications on crosstalk noise minimization M. ROCA (University of Balearic Islands, Spain), E. ISERN, F. MOLL	49
Macro-modeling strategy for digital devices and interconnects STIEVANO (Politecnico di Torino, Italy), Z. CHEN, D. BECKER, F. CANAVERO, S. GRIVET-TALOCIA, G. KATOPIS, I. MAIO	53
Characterization of the influence of different power supply styles on the electromagnetic emission of lcs by using the TEM cell method (IEC 61967-2) T. OSTERMANN (University of Linz, Austria), D. SCHNEIDER, C. BACHER, B. DEUTSCHMANN, R. JUNGREITHMAIR, W. GUT, C. LACKNER, R. KÖSSL, R. HAGELAUER	57
Electrical simulation methodology dedicated to EMC digital circuits emissions analysis on PCB J.M. DIENOT (GECET, France), Y. DEMARCQ	61
E-Learning : stakes and tendencies J.Y. PLANTEC (Iode, France)	65
Influence of the package on conducted mode emissions in a digital integrated circuit : a case study A. MERESSE (IXL-Enseirb, France), M. LEBRUN, M. RAMDANI, J.L. LEVANT	69
Power supply network modeling J.L. LEVANT (Atmel-Nantes, France), M. RAMDANI, R. PERDRIAU	75
Software detection of hardware platform failures due to electromagnetic fields G. MOTET (Lesia, France), L. TYSK	79
Neuronal approach for an accurate model of coplanar structures S. KHIREDINE (Ietr-Insa Rennes, France), M. DRISSI, R. SOARES	82
The LIMA project : e-learning related to EMC W. JOHN (IZM, Germany)	87
20:00-23:00 Dinner at "Occitania"	

15th Nov 2002	
Session: IC Modelling-1	Page
9:15 ICEM modeling of micro-controller current activity J.L. LEVANT (Atmel-Nantes, France), M. RAMDANI, R. PERDRIAU	88
9:45 Conducted emission ICEM model compare to a measure F. LAFON (Valeo, France), F. DE DARAN, O. MAURICE	92
10:15 Coffee break	
Session: IC Modelling-2	Page
10:45 IBIS models quality : the benefits of frequency-domain analysis L. GIACOTTO (Asthom, France), B. MEYNIEL, J. CHILO	95
11:15 A VHDL-AMS simulation methodology for transient supply current extraction R. PERDRIAU (Eseo, France), D. LAMBERT, M. RAMDANI, J.L. LEVANT	99
11:45 Three-pole analysis model to predict SI and EMC effects E. ENGIN (Izm Berlin, Germany), M. COENEN, H. KOEHNE, G. SOMMER, W. JOHN	105
12:15 Lunch	
Session: Reduced IC emission	Page
14:00 Behavioral EMI Models of complex digital VLSI circuits T. STEINECKE (Infineon, Germany), H. KÖHNE, M. SCHMIDT	110
14:30 EMI modeling of integrated circuits using pattern simulation L. COURAU (ST-microelectronics, France), B. GERBERT-GAILLARD	116
15:00 REGINA test mask : Research on EMC guidelines for integrated automotive circuits C. LOCHOT (Motorola, France), E. CALVET, S. BEN DHIA, E. SICARD	122
16:00 Coffee break	
Session: Improved IC susceptibility	Page
16:00 A new CMOS operational amplifier immune to EMI F. FIORI (Politecnico di Torino, Italy), P.S. CROVETTI	126
16:30 On the susceptibility of micro-controller to radio frequency interference S. BAFFREAU (Lesia, France), S. BENDHIA, M. RAMDANI, E. SICARD	130
17:00 Closing	

EXHIBITIONS / DEMONSTRATIONS

Main hall, November, 14-15th, 2002	Page
CST EFFICIENT PARAMETER EXTRACTION OF HIGH-SPEED IC-INTERCONNECTS WITH CST MICROWAVE STUDIO ® E. LEROUX	134
EADS - CCR EMC2000 : Your numerical electromagnetic laboratory on PC A. SOUBEYRAN	136
SCHAFFNER Testing in TEM cells, GTEM cells. N. PIERRE, J.L DE FRANCISCO	137
M2s Demonstration ETS-EMCO GTEM associated with a PMM 7000 EMI receiver. J.M. LELAURAIN, F. BIBAL	138